		19	Filling or coating of groove or
This Class 216 is considered to be an			through hole in a conductor
integral part of Class 156 (see the Class			with an insulator
156 schedule for the position of this		20	.Adhesive or autogenous bonding
Class ir	n schedule hierarchy). This Class		of self-sustaining preforms
retains	all pertinent definitions and		(e.g., prefabricated base,
class lines of Class 156.			etc.)
		21	Repairing circuit
		22	FORMING OR TREATING ARTICLE
		22	
			CONTAINING MAGNETICALLY
2	ETCHING OF SEMICONDUCTOR MATERIAL	0.0	RESPONSIVE MATERIAL
	TO PRODUCE AN ARTICLE HAVING A	23	FORMING OR TREATING ARTICLE
	NONELECTRICAL FUNCTION		CONTAINING A LIQUID CRYSTAL
3	FORMING OR TREATING JOSEPHSON		MATERIAL
	JUNCTION ARTICLE	24	FORMING OR TREATING OPTICAL
4	FORMING OR TREATING A SIGN OR		ARTICLE
	MATERIAL USEFUL IN A SIGN	25	.Phosphor screen
5	.Sign or material is	26	.Lens
3	electroluminescent	27	FORMING OR TREATING THERMAL INK
6	FORMING OR TREATING MATERIAL		JET ARTICLE (E.G., PRINT HEAD,
O	USEFUL IN A CAPACITOR		LIQUID JET RECORDING HEAD,
7			ETC.)
7	FORMING OR TREATING FIBROUS	28	FORMING OR TREATING AN ORNAMENTED
	ARTICLE OR FIBER REINFORCED	20	ARTICLE
	COMPOSITE STRUCTURE	29	.Wood surface treated or wood
8	FORMING OR TREATING CYLINDRICAL	49	
	OR TUBULAR ARTICLE HAVING	2.0	grain produced
	PATTERN OR DESIGN ON ITS	30	.Treating stone (e.g., marble,
	SURFACE	0.4	etc.)
9	.Forming or treating an embossing	31	.Treating glass (e.g., mirror,
	cylinder or tubular article		etc.)
10	.Forming or treating liquid	32	.Treating elemental metal or
	transfer cylinder or tubular		alloy thereof
	article (e.g., printing roll,	33	ADHESIVE OR AUTOGENOUS BONDING OF
	etc.)		TWO OR MORE SELF-SUSTAINING
11	FORMING OR TREATING AN ARTICLE		PREFORMS WHEREIN AT LEAST TWO
	WHOSE FINAL CONFIGURATION HAS		OF THE PREFORMS ARE NOT
	A PROJECTION		INTENDED TO BE REMOVED (E.G.,
12	FORMING OR TREATING MASK USED FOR		PREFABRICATED BASE, ETC.)
	ITS NONETCHING FUNCTION (E.G.,	34	.Etching improves or promotes
	SHADOW MASK, X-RAY MASK, ETC.)		adherence of preforms being
13	FORMING OR TREATING ELECTRICAL		bonded
	CONDUCTOR ARTICLE (E.G.,	35	Bonding of preform of metal or
	CIRCUIT, ETC.)		an alloy thereof to a preform
14	.Forming or treating lead frame		of a nonmetal
TÆ	or beam lead	36	.Removing at least one of the
1 5			self-sustaining preforms or a
15	Forming or treating a crossover		portion thereof
16	.Forming or treating resistive	37	ETCHING AND COATING OCCUR IN THE
4.5	material	<i>J</i> /	SAME PROCESSING CHAMBER
17	.Forming or treating of groove or	20	
	through hole	38	PLANARIZING A NONPLANAR SURFACE
18	Filling or coating of groove or	39	FORMING GROOVE OR HOLE IN A
	through hole with a conductor		SUBSTRATE WHICH IS
	to form an electrical		SUBSEQUENTLY FILLED OR COATED
	interconnection		

4.0		CE	The face of the same
40	FORMING PATTERN USING LIFT OFF	65	Using laser
11	TECHNIQUE	66	Using ion beam, ultraviolet, or
41	MASKING OF A SUBSTRATE USING	6.77	visible light
	MATERIAL RESISTANT TO AN	67	Using plasma
40	ETCHANT (I.E., ETCH RESIST)	68	Using coil to generate the
42	Resist material applied in	60	plasma
4.2	particulate form or spray	69	Using microwave to generate
43	.Adhesively bonding resist to	5 0	the plasma
4.4	substrate	70	Magnetically enhancing the
44	.Mechanically forming pattern		plasma
4.5	into a resist	71	Specific configuration of
45	.Mask is reusable (i.e., stencil)		electrodes to generate the
46	.Masking of sidewall		plasma
47	.Mask is multilayer resist	72	.Etching a multiple layered
48	.Mask is exposed to nonimaging		substrate where the etching
	radiation		condition used produces a
49	.Mask resist contains organic		different etching rate or
	compound		characteristic between at
50	Mask resist contains a color		least two of the layers of the
	imparting agent		substrate
51	.Mask resist contains inorganic	73	.Etching vapor produced by
	material		evaporation, boiling, or
52	MECHANICALLY SHAPING, DEFORMING,	- 4	sublimation
	OR ABRADING OF SUBSTRATE	74	.Etching inorganic substrate
53	.Nongaseous phase etching	75	Substrate contains elemental
54	PATTERN OR DESIGN APPLIED BY		metal, alloy thereof, or metal
	TRANSFER		compound
55	HEATING OR BAKING OF SUBSTRATE	76	Etching of substrate
	PRIOR TO ETCHING TO CHANGE THE		containing at least one
	CHEMICAL PROPERTIES OF		compound having at least one
	SUBSTRATE TOWARD THE ETCHANT		oxygen atom and at least one
56	ETCHING TO PRODUCE POROUS OR		metal atom
	PERFORATED ARTICLE	77	Etching of substrate
57	GAS PHASE AND NONGASEOUS PHASE		containing elemental aluminum,
	ETCHING ON THE SAME SUBSTRATE		or an alloy or compound
58	GAS PHASE ETCHING OF SUBSTRATE	П.О	thereof
59	.With measuring, testing, or	78	Etching of substrate
	inspecting		containing elemental copper,
60	By optical means or of an		or an alloy or compound
	optical property	70	thereof
61	By electrical means or of an	79	Etching silicon containing
	electrical property	0.0	substrate
62	.Irradiating, ion implanting,	80	Silicon containing substrate
	alloying, diffusing, or	0.1	is glass
	chemically reacting the	81	. Etching elemental carbon
	substrate prior to etching to	0.0	containing substrate
	change properties of substrate	83	NONGASEOUS PHASE ETCHING OF
	toward the etchant	0.4	SUBSTRATE
63	.Application of energy to the	84	.With measuring, testing, or
	gaseous etchant or to the	0.5	inspecting
	substrate being etched	85	By optical means or of an
64	Etchant is devoid of	0.5	optical property
	chlorocarbon or fluorocarbon	86	By electrical means or of an
	compound (e.g., C.F.C., etc.)		electrical property

87	.Irradiating, ion implanting, alloying, diffusing, or chemically reacting the	109Etchant contains fluoride ion
	substrate prior to ethching to change properties of substrate toward the etchant	FOREIGN ART COLLECTIONS
88	.Using film of etchant between a stationary surface and a moving surface (e.g., chemical lapping, etc.)	FOR 000 CLASS-RELATED FOREIGN DOCUMENTS
89	<pre>Etchant contains solid particle (e.g., abrasive for polishing, etc.)</pre>	
90	Relative movement between the substrate and a confined pool of etchant	
91	Rotating, repeated dipping, or advancing movement of substrate	
92	Projecting etchant against a moving substrate or controlling the angle or pattern projection of the etchant or controlling the angle or pattern of movement of the substrate	
93	Recycling, regenerating, or rejunevating etchant	
94	Etching using radiation (e.g., laser, electron-beam, ion-beam, etc.)	
95	.Substrate is multilayered	
96	.Etching inorganic substrate	
97	Substrate is glass	
98	Frosting glass	
99	Substrate contains silicon or silicon compound	
100	Substrate contains elemental metal, alloy thereof, or metal compound	
101	Etching of a compound containing at least one oxygen atom and at least one metal atom	
102	Metal is elemental aluminum, an alloy, or compound thereof	
103	Etchant contains acid	
104	Etchant contains fluoride ion	
105	Metal is elemental copper, an alloy, or compound thereof	
106	Etchant contains acid	
107	Etchant contains fluoride ion	
108	Etchant contains acid	